

## C Series



- Excellent shock resistance and environmental capability
- Low power consumption
- Suitable for time-keeping of clock and microcomputer

### PART NUMBER GUIDE

**C-146 - 32.768 - 20 - J - 125**

**PACKAGE TYPE**

**C-146** : SMD type 7.0x1.5x1.4mm

**LOAD CAPACITANCE**

**125** : 12,5pF

**OPERATING TEMPERATURE**  
**TABLE 1**

**FREQUENCY**

**32.768KHz**

**FREQUENCY TOLERANCE AT 25°C**

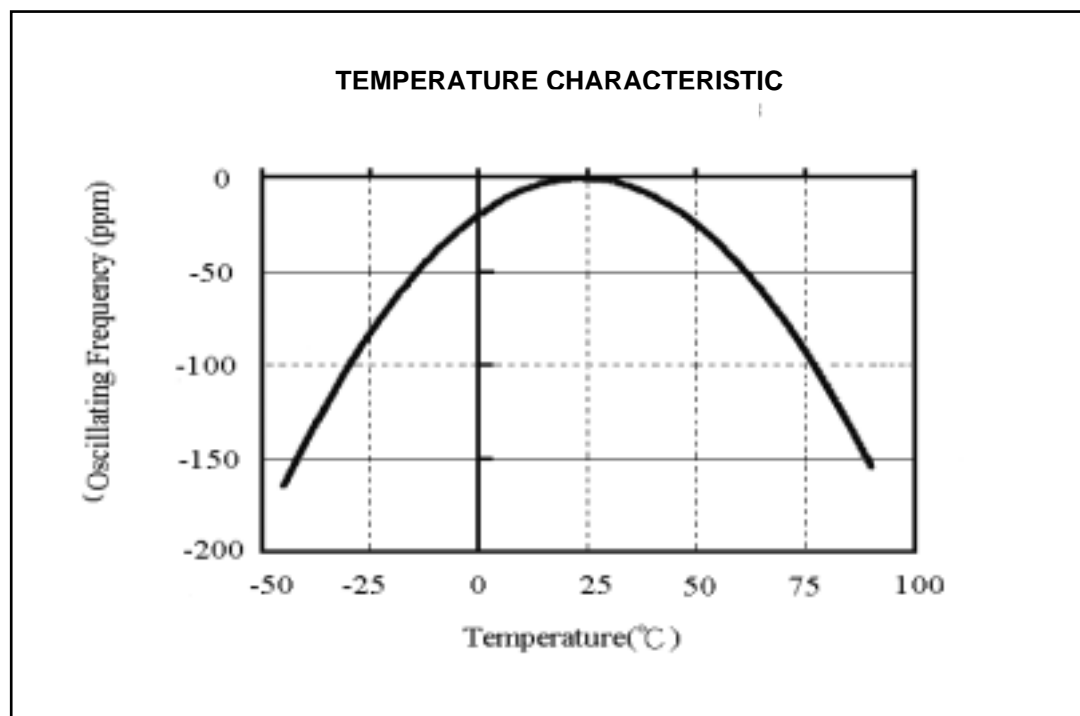
**±20 ppm (STD)**

### ELECTRICAL SPECIFICATIONS

MODEL	C-146 serie
Nominal Frequency	32.768KHz
Frequency Tolerance (at 25°C)	±20ppm
Operating Temperature Range	-40 to +85°C(STD)
Storage Temperature Range	-55°C to +125°C
Turnover Temperature	25°C ±5°C
Temperature Coefficient (frequency)	-0.04ppm/ °C <sup>2</sup> Max
Load Capacitance (CL)	12.5pF
Drive Level	1.0 μWMax
Series Resistance (ESR)	65kΩ Max
Motional Capacitance	1.80pF to 2.00pF
Shunt Capacitance (Co)	0.8pF Typ.
Aging (at 25°C)	± 3ppm/year Max

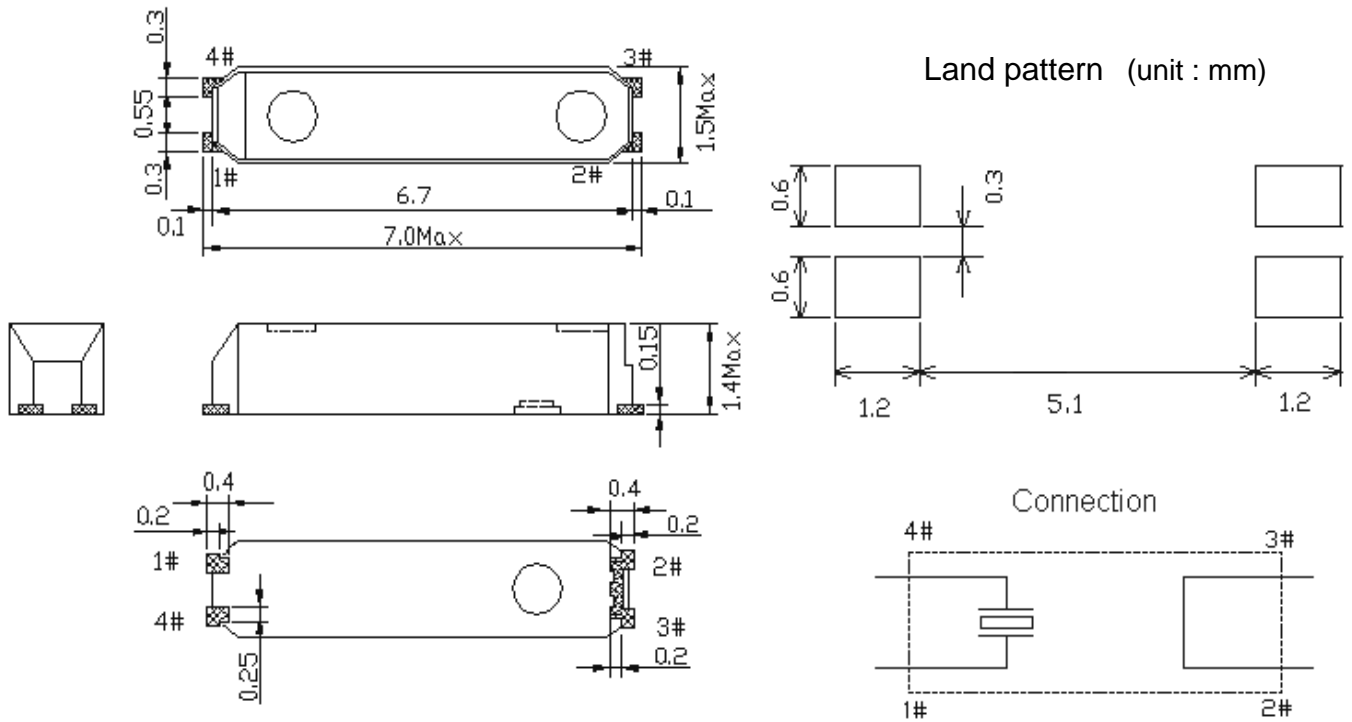
TABLE 1

OPERATING TEMPERATURE RANGE	
-10~+60°C	A
-20~+60°C	B
0~+70°C	C
-10~+70°C	D
-20~+70°C	E
-30~+60°C	F
-20~+85°C	G
-30~+70°C	H
-30~+85°C	I
-40~+85°C	J



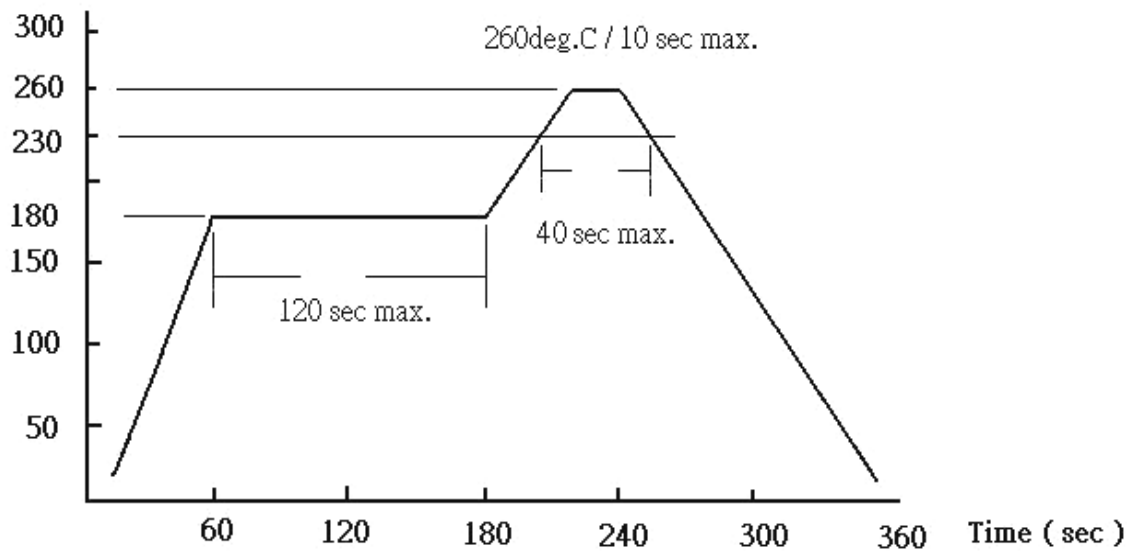
**MECHANICAL DIMENSION**

**C-146**



**SOLDERING REFLOW**

Temp. (deg.C)



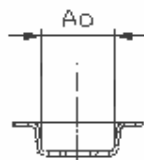
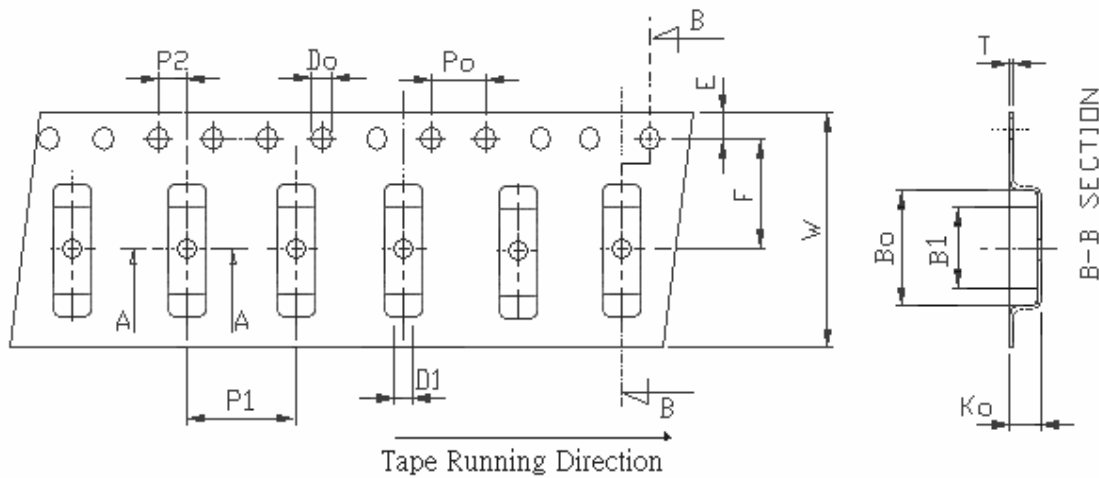
<b>SPECIFICATIONS OF CRYSTAL UNITS</b>
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**Reliability Test** ( applicable to 49(50) type .U type and Tuning Fork X'tal )

Test Items	Test Condition	Specification	
		Dip	SMD
1. Gross Leak Test	FC-40 125 /30sec	No continuous bubble	
2. Fine Leak Test	Bombing of He 4kg/cm <sup>2</sup> for 2 hours	Less than 5*10 <sup>-8</sup> atm.c.c./sec, Helium	
3. Drop Test	Free dropped a. ~19.999MHz(Fund.) →100 cm height b. 20~29.999MHz(Fund.) →50 cm height c. 30~ MHz(Fund.) →20 cm height on a hard wooden board for 3 times ( board is thickness more than 30 mm)	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.
4. Vibration Test	Freq. range: 10~55Hz Peak to peak amplitude:1.5mm 3 direction(X,Y,Z) , each 60min.	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.
5. Resistance to Soldering Test	a. IR Reflow furnace with the condition 2 times. Peak temp.260±3 , 10sec( Min.)	NA	F ±10PPM , C.I within spec. For SMD type only.
	b. Dip terminals in a 260±5 solder bath for 5±0.5 sec.	At least 90% of each dipped area shall be covered by fresh solder. For DIP type only.	NA
6. Bending Test	Bending cycle : 1 cycle 0° - > 45° -> 0° -> 45° -> 0°	F ±5PPM , C.I within spec. For DIP type only.	NA
7. Share Test	Weight : 10N, Test duration : 10±1 sec	NA	F ±10PPM , C.I within spec. For SMD type only.
8. Low Temp. Exposure Test	-40±3 , 240±12 hrs	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.
9. Aging Test	85±3 , 240±12hrs	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.
10. High Temp. & Humidity Test	+85 ±5 & 85%±5% R.H. , 240±12 hrs	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.
11. Temperature Cycling Test	-25±3 /15±3min ~ +85±3 /15±3min 15cycles	F ± 10PPM , C.I within spec.	F ±10PPM , C.I within spec.

**SPECIFICATIONS OF TAPE & REEL**

**Taping**



A-A SECTION

$A_o = \underline{1.55 \pm 0.10} \text{ mm}$

$B_o = \underline{7.20 \pm 0.10} \text{ mm}$

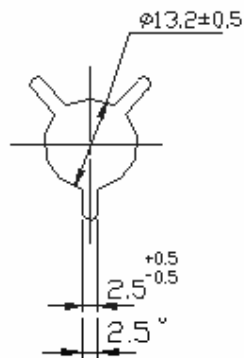
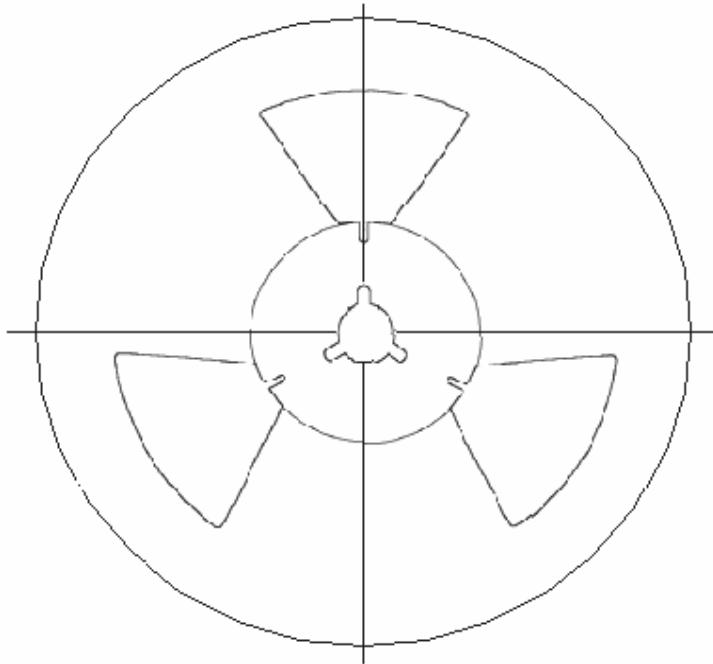
$K_o = \underline{1.50 \pm 0.10} \text{ mm}$

Unit: mm

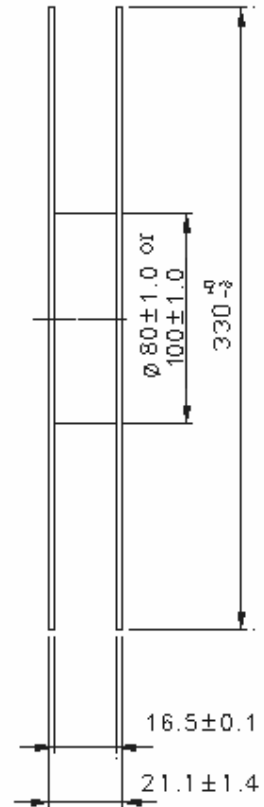
Symbol	Spec.
B1	$4.80 \pm 0.20$
Po	$4.00 \pm 0.10$
P1	$8.00 \pm 0.10$
P2	$2.00 \pm 0.10$
Do	$1.50^{+0.1}_0$
D1	1.0 (min)
E	$1.75 \pm 0.10$
F	$7.50 \pm 0.10$
10Po	$40.0 \pm 0.10$
W	$16.0 \pm 0.30$
T	$0.30 \pm 0.05$

SPECIFICATIONS OF TAPE & REEL

Reel



Q'ty:3000pcs/reel



Unit:mm

**Pb-free compliance**

Component and Assembly Pb content shall be less than 0.1% by weight of the device (in accordance with IPC/EIA J-STD-006, European ROHS 3 Directive (EU) 2015/865).

**Product Information**

For a product to be **RoHS** compliant, it must satisfy several conditions:

- Contain no more than the specified limits of the target hazardous substances set out in the RoHS Directive
- Able to withstand Pb-free 260°C solder reflow profile below
- External packaging and terminations are Pb-free
- Internal PCB, components, solders, and terminations are Pb-free